

Summary (ABSTRACT)

The present invention relates to a device for measuring the distribution of selected properties of materials, said device comprises an emitter of electromagnetic radiation and
 5 furthermore at least one sensor of a first type. The emitter emits electromagnetic radiation in a selected frequency range towards said materials and a sensor of the first type detects electromagnetic radiation in a selected frequency range coming from said materials. The detected electromagnetic radiation
 10 having been emitted by said emitter. The device also comprises means to generate a three dimensional image contour information regarding the said material's position in space, and an analyser which (a) receives information from said sensors and (b) processes this information and (c) generates
 5 signals containing information about the distribution of said properties as output. The invention also relates to a system and a method for measuring the distribution of selected properties of materials.